

Attorney's Docket No.: 12671-035001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Huy A. Bui

Art Unit : 2881

Serial No.: 10/649,586

Examiner: Unknown

Filed

: August 26, 2003

Title

: OPTIMIZING SAMPLE PLATE PROCESSING IN A MALDI-TOF MASS

SPECTROMETER

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

6/24/04 Date:

Reg. No. 34,609

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

June 24, 2004	
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Nikia M. Mc Nillion

Typed or Printed Name of Person Signing Certificate

Sheet	1	of	1

. Department of Commerce atent and Trademark Office Substitute Form FTO-1468 (Modified) Attorney's Docket No. Application No. 12671-035001 10/649,586 Applicant Inform ire Statement Huy A. Bui (Use several sheets if necessary) Filing Date Group Art Unit August 26, 2003 2881 (37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	US 2002/0191864 A1	12/19/2002	Lennon et al.			
	AB	US 2003/0052859 A1	03/20/2003	Finley			
	AC	5,969,350	10/19/1999	Kerley et al.			
	AD	6,498,690 B2	12/24/2002	Ramm et al.			
	AE						
	AF						_
	AG				i.		
	AH						
	AI						
	AJ						
	AK					-	

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
•	AL					•		
	AM	-	·					
	AN		·					
	AO							
	AP							٠

	Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner	Desig.				
Initial	ID	Document			
	AQ	Justin W. Torpey et al., "Validation Of Pattern Recognition Software With Automated Protein Identification Using An Orthogonal MALDI-QqTQF Mass Spectrometer", Applied BioSystems and MDS Sciex, 52 nd Annual ASMS Conference, June 2002			
	AR				
	AS				
	АТ				

Examiner Signature	Date Considered					
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with						
next communication to applicant.						